International Rectifier

IRF3717

HEXFET® Power MOSFET

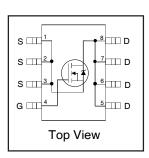
Applications

- Synchronous MOSFET for Notebook Processor Power
- Synchronous Rectifier MOSFET for Isolated DC-DC Converters in Networking Systems

V _{DSS}	R _{DS(on)} max	I _D
20V	4.4 m Ω @ $V_{GS} = 10V$	20A

Benefits

- Ultra-Low Gate Impedance
- Very Low R_{DS(on)}
- Fully Characterized Avalanche Voltage and Current





Absolute Maximum Ratings

	Parameter	Max.	Units
V_{DS}	Drain-to-Source Voltage	20	V
V _{GS}	Gate-to-Source Voltage	± 20	
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V	20	
I _D @ T _A = 70°C	Continuous Drain Current, V _{GS} @ 10V	16	А
I _{DM}	Pulsed Drain Current ①	160	
P _D @T _A = 25°C	Power Dissipation	2.5	W
P _D @T _A = 70°C	Power Dissipation	1.6	
	Linear Derating Factor	0.02	W/°C
TJ	Operating Junction and	-55 to + 150	°C
T _{STG}	Storage Temperature Range		

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\theta JL}$	Junction-to-Drain Lead		20	°C/W
$R_{\theta JA}$	Junction-to-Ambient ④		50	

Static @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
BV _{DSS}	Drain-to-Source Breakdown Voltage	20	_		V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temp. Coefficient		0.014		V/°C	Reference to 25°C, I _D = 1mA
R _{DS(on)}	Static Drain-to-Source On-Resistance		3.7	4.4	mΩ	V _{GS} = 10V, I _D = 20A ③
			4.8	5.7	1	V _{GS} = 4.5V, I _D = 16A ③
$V_{GS(th)}$	Gate Threshold Voltage	1.55	2.0	2.45	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
$\Delta V_{GS(th)}/\Delta T_{J}$	Gate Threshold Voltage Coefficient		-5.4		mV/°C	
I _{DSS}	Drain-to-Source Leakage Current			1.0	μΑ	$V_{DS} = 16V, V_{GS} = 0V$
				150	1	$V_{DS} = 16V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
I _{GSS}	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
	Gate-to-Source Reverse Leakage			-100	1	V _{GS} = -20V
gfs	Forward Transconductance	57			S	V _{DS} = 10V, I _D = 16A
Q _g	Total Gate Charge		22	33		
Q _{gs1}	Pre-Vth Gate-to-Source Charge		6.8		1	$V_{DS} = 10V$
Q _{gs2}	Post-Vth Gate-to-Source Charge		2.2		nC	$V_{GS} = 4.5V$
Q_{gd}	Gate-to-Drain Charge		7.3			I _D = 16A
Q_{godr}	Gate Charge Overdrive		5.7		1	See Fig. 16
Q _{sw}	Switch Charge (Q _{gs2} + Q _{gd})		9.5		1	
Q _{oss}	Output Charge		12		nC	$V_{DS} = 10V, V_{GS} = 0V$
t _{d(on)}	Turn-On Delay Time		12			$V_{DD} = 10V, V_{GS} = 4.5V$
t _r	Rise Time		14		1	I _D = 16A
t _{d(off)}	Turn-Off Delay Time		15		ns	Clamped Inductive Load
t _f	Fall Time	_	6.0		1	
C _{iss}	Input Capacitance	_	2890			$V_{GS} = 0V$
Coss	Output Capacitance	_	930		pF	$V_{DS} = 10V$
C _{rss}	Reverse Transfer Capacitance		430		1	f = 1.0MHz

Avalanche Characteristics

	Parameter	Тур.	Max.	Units
E _{AS}	Single Pulse Avalanche Energy ②		32	mJ
I _{AR}	Avalanche Current ①		16	Α

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			20		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			160		integral reverse
	(Body Diode) ①					p-n junction diode.
V_{SD}	Diode Forward Voltage			1.0	V	$T_J = 25$ °C, $I_S = 16A$, $V_{GS} = 0V$ ③
t _{rr}	Reverse Recovery Time		22	32		$T_J = 25$ °C, $I_F = 16A$, $V_{DD} = 10V$
Q_{rr}	Reverse Recovery Charge		13	19	nC	di/dt = 100A/μs ③

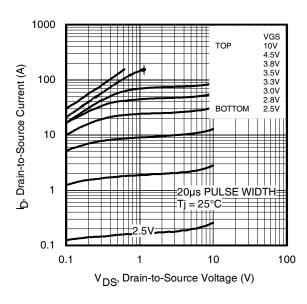
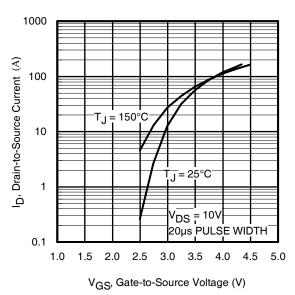


Fig 1. Typical Output Characteristics

Fig 2. Typical Output Characteristics



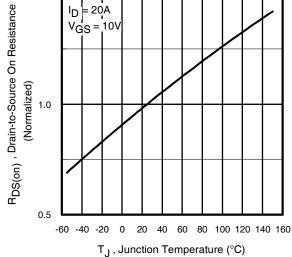


Fig 3. Typical Transfer Characteristics

Fig 4. Normalized On-Resistance vs. Temperature

1000.00

100.00

10.00

1.00

0.10

0.0

0.2

I_{SD}, Reverse Drain Current (A)

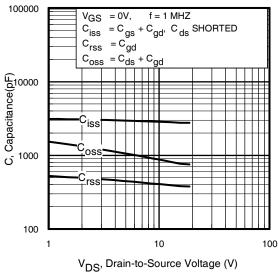


Fig 5. Typical Capacitance vs. Drain-to-Source Voltage

T_J = 150°C

0.4



1.2

1.4

1.0

Fig 7. Typical Source-Drain Diode Forward Voltage

0.6

 V_{SD} , Source-to-Drain Voltage (V)

0.8

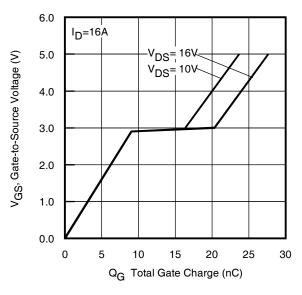


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

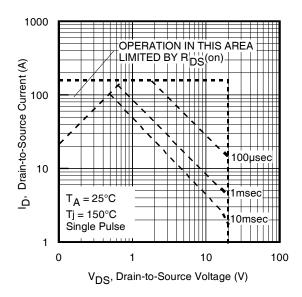
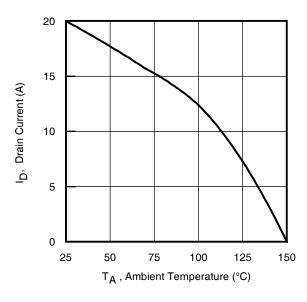


Fig 8. Maximum Safe Operating Area

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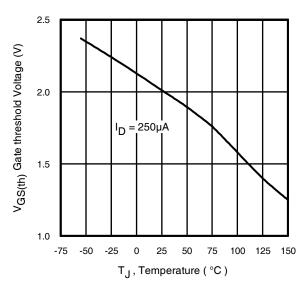


Fig 9. Maximum Drain Current vs. Ambient Temperature

Fig 10. Threshold Voltage vs. Temperature

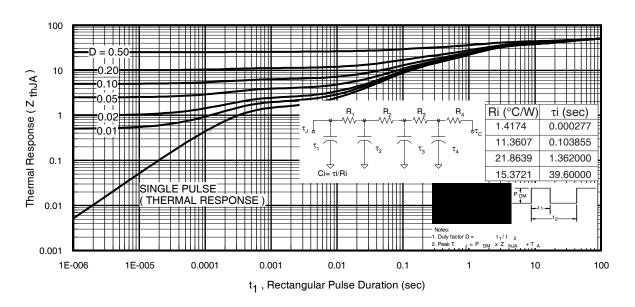


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient

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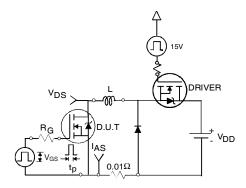


Fig 12a. Unclamped Inductive Test Circuit

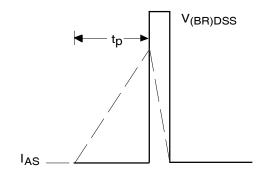


Fig 12b. Unclamped Inductive Waveforms

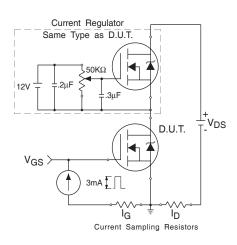


Fig 13. Gate Charge Test Circuit

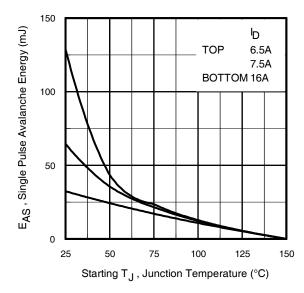


Fig 12c. Maximum Avalanche Energy vs. Drain Current

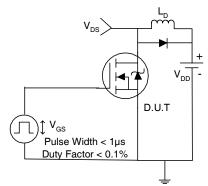


Fig 14a. Switching Time Test Circuit

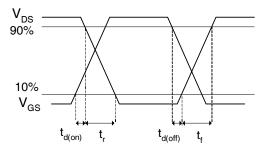


Fig 14b. Switching Time Waveforms www.irf.com

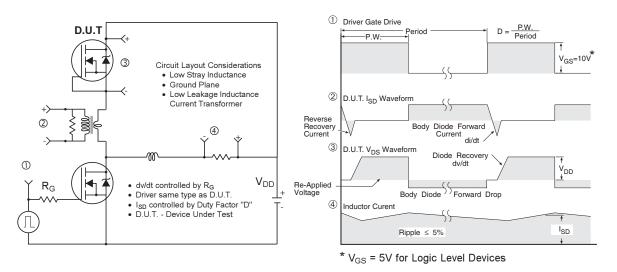


Fig 15. Peak Diode Recovery dv/dt Test Circuit for N-Channel HEXFET® Power MOSFETs

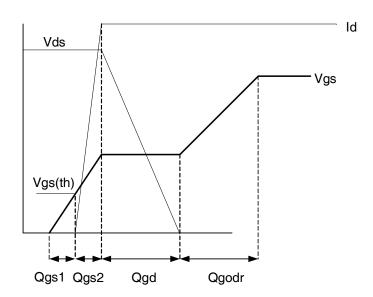


Fig 16. Gate Charge Waveform

Power MOSFET Selection for Non-Isolated DC/DC Converters

Control FET

Special attention has been given to the power losses in the switching elements of the circuit - Q1 and Q2. Power losses in the high side switch Q1, also called the Control FET, are impacted by the $R_{\rm ds(on)}$ of the MOSFET, but these conduction losses are only about one half of the total losses.

Power losses in the control switch Q1 are given by;

$$P_{loss} = P_{conduction} + P_{switching} + P_{drive} + P_{output}$$

This can be expanded and approximated by:

$$\begin{split} P_{loss} &= \left(I_{rms}^{2} \times R_{ds(on)}\right) \\ &+ \left(I \times \frac{Q_{gd}}{i_{g}} \times V_{in} \times f\right) + \left(I \times \frac{Q_{gs2}}{i_{g}} \times V_{in} \times f\right) \\ &+ \left(Q_{g} \times V_{g} \times f\right) \\ &+ \left(\frac{Q_{oss}}{2} \times V_{in} \times f\right) \end{split}$$

This simplified loss equation includes the terms ${\rm Q_{gs2}}$ and ${\rm Q_{oss}}$ which are new to Power MOSFET data sheets.

 Q_{gs2} is a sub element of traditional gate-source charge that is included in all MOSFET data sheets. The importance of splitting this gate-source charge into two sub elements, Q_{gs1} and Q_{gs2} , can be seen from Fig. 16.

 Q_{gs2} indicates the charge that must be supplied by the gate driver between the time that the threshold voltage has been reached and the time the drain current rises to I_{dmax} at which time the drain voltage begins to change. Minimizing Q_{gs2} is a critical factor in reducing switching losses in Q1.

 $\rm Q_{oss}$ is the charge that must be supplied to the output capacitance of the MOSFET during every switching cycle. Figure A shows how $\rm Q_{oss}$ is formed by the parallel combination of the voltage dependant (nonlinear) capacitance's $\rm C_{ds}$ and $\rm C_{dg}$ when multiplied by the power supply input buss voltage.

Synchronous FET

The power loss equation for Q2 is approximated by;

$$\begin{split} P_{loss} &= P_{conduction} + P_{drive} + P_{output}^* \\ P_{loss} &= \left(I_{rms}^2 \times R_{ds(on)}\right) \\ &+ \left(Q_g \times V_g \times f\right) \\ &+ \left(\frac{Q_{ass}}{2} \times V_{in} \times f\right) + \left(Q_{rr} \times V_{in} \times f\right) \end{split}$$

*dissipated primarily in Q1.

For the synchronous MOSFET Q2, $R_{\text{ds(on)}}$ is an important characteristic; however, once again the importance of gate charge must not be overlooked since it impacts three critical areas. Under light load the MOSFET must still be turned on and off by the control IC so the gate drive losses become much more significant. Secondly, the output charge Q_{oss} and reverse recovery charge Q_{r} both generate losses that are transfered to Q1 and increase the dissipation in that device. Thirdly, gate charge will impact the MOSFETs' susceptibility to Cdv/dt turn on.

The drain of Q2 is connected to the switching node of the converter and therefore sees transitions between ground and $V_{\rm in}$. As Q1 turns on and off there is a rate of change of drain voltage dV/dt which is capacitively coupled to the gate of Q2 and can induce a voltage spike on the gate that is sufficient to turn the MOSFET on, resulting in shoot-through current . The ratio of $Q_{\rm gd}/Q_{\rm gs1}$ must be minimized to reduce the potential for Cdv/dt turn on.

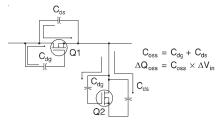


Figure A: Q ... Characteristic

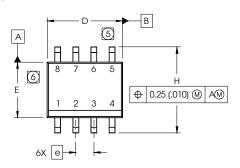
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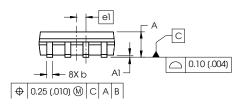
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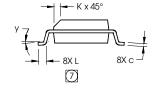
SO-8 Package Details

Dimensions are shown in millimeters (inches)



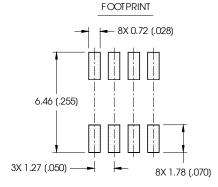
DIM	INC	HES	MILLIM	ETERS	
DIIVI	MIN	MAX	MIN	MAX	
Α	.0532	.0688	1.35	1.75	
A1	.0040	.0098	0.10	0.25	
b	.013	.020	0.33	0.51	
С	.0075	.0098	0.19	0.25	
D	.189	.1968	4.80	5.00	
Е	.1497	.1574	3.80	4.00	
е	.050 B	ASIC	1.27 BASIC		
e1	.025 B	ASIC	0.635 BASIC		
Н	.2284	.2440	5.80	6.20	
K	.0099	.0196	0.25	0.50	
L	.016	.050	0.40	1.27	
У	0°	8°	0°	8°	





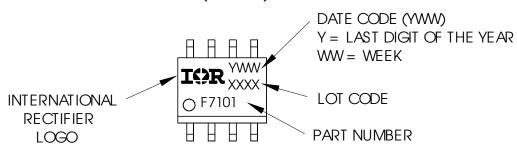
NOTES:

- 1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
- 2. CONTROLLING DIMENSION: MILLIMETER
- 3. DIMENSIONS ARE SHOWN IN MILLIMETERS (INCHES).
- 4. OUTLINE CONFORMS TO JEDEC OUTLINE MS-012AA
- (5) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.15 (.006).
- (6) DIMENSION DOES NOT INCLUDE MOLD PROTRUSIONS. MOLD PROTRUSIONS NOT TO EXCEED 0.25 (.010).
- (7) DIMENSION IS THE LENGTH OF LEAD FOR SOLDERING TO A SUBSTRATE.



SO-8 Part Marking

EXAMPLE: THIS IS AN IRF7101 (MOSFET)

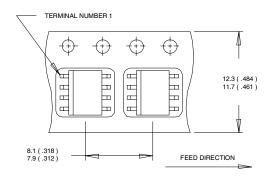


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SO-8 Tape and Reel

Dimensions are shown in millimeters (inches)



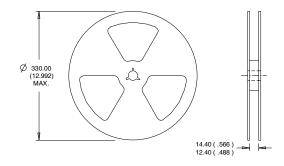
NOTES:

- NOTES:

 1. CONTROLLING DIMENSION : MILLIMETER.

 2. ALL DIMENSIONS ARE SHOWN IN MILLIMETERS(INCHES).

 3. OUTLINE CONFORMS TO EIA-481 & EIA-541.



NOTES:

- CONTROLLING DIMENSION : MILLIMETER.
 OUTLINE CONFORMS TO EIA-481 & EIA-541.

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature.
- ② Starting $T_J = 25$ °C, L = 0.26mH, $R_G = 25\Omega$, $I_{AS} = 16$ A.
- 3 Pulse width \leq 400 μ s; duty cycle \leq 2%.
- When mounted on 1 inch square copper board.

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105

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